

<b>INFORMATION DISCLOSURE CITATION</b> <i>(Use several sheets if necessary)</i>	<b>Docket Number (Optional)</b> <b>TWI-11720</b>	<b>Application Number</b> <b>NEW</b>
	<b>Applicant(s)</b> <b>Louis N. Koppel et al.</b>	
	<b>Filing Date</b> <b>HEREWITH</b>	<b>Group Art Unit</b> <b>Unknown</b>

### U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE
	*AA	5,042,951	08/27/1991	Gold et al.	356	369	09/19/1989
	*AB	5,412,473	05/02/1995	Rosencwaig et al.	356	351	07/16/1993
	*AC	5,475,728	12/12/1995	Smith et al.	378	81	08/02/1993
	*AD	5,619,548	04/08/1997	Koppel	378	70	08/11/1995
	*AE	5,878,106	03/02/1999	Fujiwara	378	79	05/29-96
	*AF	5,923,720	07/13/1999	Barton et al.	378	84	06/17/1997
	*AG	6,041,098	03/21/2000	Touryanski et al.	378	70	02/02/1998
	*AH	6,069,934	05/30/2000	Verman et al.	378	73	04/07/1998

### FOREIGN PATENT DOCUMENTS

	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	*AI	144 956	11/12/1980	Germany	G01B	15/02		X
	*AJ	WO 92/08104	05/14/1992	PCT	G01B	11/24		
	*AK	20011116705	04/27/2001	Japan	G01N	23/207	Abstract	

### OTHER DOCUMENTS

*(Including Author, Title, Date, Pertinent Pages, Etc.)*

	*AL	K. Sakurai et al., "Fourier Analysis of Interference Structure in X-Ray Specular Reflection from Thin Films," <i>Jpn. J. Appl. Phys.</i> , Vol. 31, 1992, pp. L113-L115.
	*AM	K.N. Stoev et al., "Review on grazing incidence X-ray spectrometry and reflectometry," <i>Spectrochimica Acta Part B</i> , Vol. 54, 1999, pp. 41-82.
	*AN	N. Wainfan et al., "Density Measurements of Some Thin Copper Films," <i>Journal of Applied Physics</i> , Vol. 30, No. 10, October 1959, pp. 1604-1609.
	*AO	J.P. Sauro et al., "Some Observations on the Interference Fringes Formed by X Rays Scattered from Thin Films," <i>Physical Review</i> , Vol. 143, No. 1, March 1966, pp. 439-443.
	*AP	K. Sakurai et al., "Analysis of thin films by X-ray scattering at grazing incidence," <i>SPRING-8 User Experiment Report No. 2 (1998 A)</i> , March 1999, p. 162.

<b>Examiner</b>	<b>Date Considered</b>
<b>Examiner: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</b>	

PATENT

-1-

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of

Louis N. Koppel et al.

Application No.: NEW

Filed: HEREWITH

For: CALIBRATION AND ALIGNMENT  
OF X-RAY REFLECTOMETRIC  
SYSTEM

Group Art Unit: Unknown

Examiner: Unknown

**INFORMATION DISCLOSURE  
STATEMENT**121 Spear Street, Suite 290  
San Francisco, CA 94105  
(415) 512-1312M/S PATENT APPLICATION  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

Applicant(s) submit(s) herewith patents, publications or other information [attached hereto and listed on the attached Form PTO-1449 (modified)] of which they are aware, which they believe(s) may be material to the examination of this application and in respect of which there may be a duty to disclose in accordance with 37 CFR § 1.56.

This Information Disclosure Statement:

- (a) ☒ accompanies the new patent application submitted herewith. 37 CFR § 1.97(a).
- (b) ☐ is filed within three months after the filing date of the application or within three months after the date of entry of the national stage of a PCT application as set forth in 37 CFR § 1.491.
- (c) ☐ as far as is known to the undersigned, is filed before the mailing date of a first Office Action on the merits, or before a first office action after filing a Request for Continued Examination under §1.114.
- (d) ☐ is filed after the first office action and more than three months after the application's filing date or PCT national stage date of entry filing but, as far as is known to the undersigned, prior to the mailing date of either a final rejection or a

Atty Docket No.: TWI-11720

notice of allowance, whichever occurs first, and is accompanied by either the fee (\$180) set forth in 37 CFR § 1.17(p) or a certification as specified in 37 CFR § 1.97(e), as checked below.

- (e) ☐ is filed after the mailing date of either a final rejection or a notice of allowance, whichever occurred first, and the Issue Fee has not been paid, and is accompanied by the fee (\$130) set forth in 37 CFR § 1.17(i)(1) and a certification as specified in 37 CFR § 1.97(e), as checked below. This document is to be considered as a petition requesting consideration of the information disclosure statement.

[If either of boxes (d) or (e) is checked above, the following "certification" under 37 CFR § 1.97(e) may need to be completed.] The undersigned certifies that:

- (f) ☐ Each item of information contained in the information disclosure statement was cited in a communication mailed from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this information disclosure statement.
- (g) ☐ No item of information contained in this information disclosure statement was cited in a communication mailed from a foreign patent office in a counterpart foreign application or, to the knowledge of the undersigned after making reasonable inquiry, was known to any individual designated in 37 CFR § 1.56(c) more than three months prior to the filing of this information disclosure statement.

A list of the patent(s) or publication(s) is set forth on the attached Form PTO-1449 (Modified).

A copy of the items on PTO-1449 (Modified) is supplied herewith:

- (h) ☐ each (i) ☒ none (j) ☐ only those listed below:

---

Those patent(s) or publication(s) which are marked with an asterisk (\*) in the attached form PTO-1449 (Modified) are not supplied because they were previously cited by or submitted to the Office in a prior application no. 10/124,776, filed April 17, 2002, and application no. 09/527,389, filed March 16, 2000, and relied upon in this application for an earlier filing date under 35 U.S.C. § 120.

A concise explanation of relevance of the items listed on form PTO-1449 (Modified) is:

- (k) ☒ not given

- (l) ☐ given for each listed item
- (m) ☐ given for only non-English language listed item(s) [Required]
- (n) ☐ is in the form of an English language copy of a Search Report from a foreign patent office, issued in a counterpart application, which refers to the relevant portions of the references [copy attached].

The Examiner is reminded that a "concise explanation of the relevance" of the submitted items "may be nothing more than identification of the particular figure or paragraph of the patent or publication which has some relation to the claimed invention," MPEP § 609.

While the information and references disclosed in this Information Disclosure Statement may be "material" pursuant to 37 CFR § 1.56, it is not intended to constitute an admission that any patent, publication or other information referred to therein is "prior art" for this invention unless specifically designated as such.

In accordance with 37 CFR § 1.97(g), the filing of this Information Disclosure Statement shall not be construed to mean that a search has been made or that no other material information as defined in 37 CFR § 1.56(a) exists. It is submitted that the Information Disclosure Statement is in compliance with 37 CFR § 1.98 and MPEP § 609 and the Examiner is respectfully requested to consider the listed references.

Respectfully submitted,

STALLMAN & POLLOCK LLP

Dated: August 14, 2003

By: 

Brian J. Keating  
Reg. No. 39,520

Attorneys for Applicant(s)